TOSHIBA Field Effect Transistor Silicon P, N Channel MOS Type (U-MOS IV / U-MOS III)

TPCP8402

Portable Equipment Applications Motor Drive Applications DC-DC Converter Applications

- Lead(Pb)-Free
- Low drain-source ON resistance : P Channel RDS (ON) = 60 m Ω (typ.) N Channel RDS (ON) = 38 m Ω (typ.)
- High forward transfer admittance : P Channel $|Y_{fs}| = 6.0 \text{ S} \text{ (typ.)}$
 - N Channel $|Y_{fs}| = 7.0 \text{ S (typ.)}$
- Low leakage current : P Channel $I_{DSS} = -10 \ \mu A \ (V_{DS} = -30 \ V)$ N Channel $I_{DSS} = 10 \ \mu A \ (V_{DS} = 30 \ V)$
- Enhancement mode : P Channel V_{th} = -0.8 to -2.0 V (V_{DS} = -10 V, I_D = -1mA) N Channel V_{th} = 1.3 to 2.5 V (V_{DS} = 10 V, I_D = 1mA)

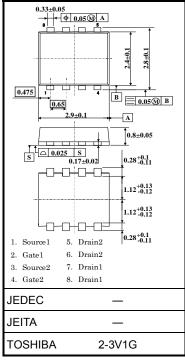
Absolute Maximum Ratings (Ta = 25°C)

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С	haracteristics	Symbol	Rating		Unit		
Drain-source	voltage	V _{DSS}	-30	30	V		
Drain-gate vo	ltage (R _{GS} = 20 kΩ)	V _{DGR}	-30	30	V		
Gate-source	voltage	V _{GSS}	±20	±20	V		
Drain	DC (Note 1)	Ι _D	-3.4	4.2	Α		
current	Pulse (Note 1)	I _{DP}	-13.6	16.8	A		
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	1.48	1.48			
(t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P _{D (2)}	1.23	1.23	w		
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	0.58	0.58			
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.36	0.36			
Single pulse a (Note 4)	avalanche energy	Eas	0.75	2.86	mJ		
Avalanche cu	rrent	I _{AR}	-1.7	2.1	Α		
	alanche energy value at dual operation (Note 2a, 3b, 5)	E _{AR}	0.12		mJ		
Channel temp	perature	T _{ch}	150		°C		
Storage temp	erature range	T _{stg}	-55~150		°C		

Note: For Notes 1 to 6, refer to the next page.

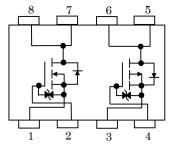
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with caution.

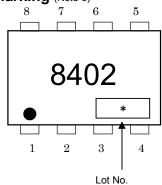


Weight: 0.017 g (typ.)

Circuit Configuration



Marking (Note 6)

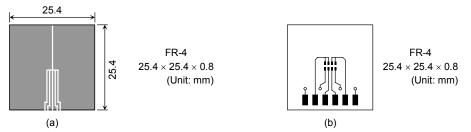


Thermal Characteristics

Charae	Symbol	Max	Unit		
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	84.5	°C/W	
	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	101.6	0/10	
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	215.5	°C/W	
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	347.2	C/VV	

Note 1: The channel temperature should not exceed 150°C during use.

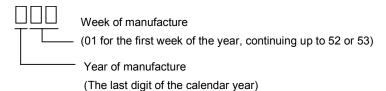
Note 2: (a) Device mounted on a glass-epoxy board (a) (b) Device mounted on a glass-epoxy board (b)



Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is only applied to one device.)

- b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is evenly applied to both devices.)
- Note 4: P Channel: $V_{DD} = -24 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 0.2 mH, $R_G = 25 \Omega$, $I_{AR} = -1.7 \text{ A}$ N Channel: $V_{DD} = 24 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 0.5 mH, $R_G = 25 \Omega$, $I_{AR} = 2.1 \text{ A}$
- Note 5: Repetitive rating: pulse width limited by maximum channel temperature
- Note 6: on the lower left of the marking indicates Pin 1.

※ Weekly code (3 digits):



P-ch

Electrical Characteristics (Ta = 25°C)

Cha	aracteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	$V_{GS} = \pm 16 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	_		±10	μA
Drain cut-off current		I _{DSS}	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	_	10	μA
Drain-source breakdown voltage		V (BR) DSS	$I_D = -10$ mA, $V_{GS} = 0$ V	-30	_	_	v
		V (BR) DSX	$I_D = -10 \text{ mA}, V_{GS} = 20 \text{ V}$	-15	_	_	v
Gate threshold vo	oltage	V _{th}	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8	—	-2.0	V
Drain-source ON resistance		Dec (com	$V_{GS} = -4.5 \text{ V}, \ I_D = -1.7 \text{ A}$	_	80	105	mΩ
		R _{DS} (ON)	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -1.7 \text{ A}$	_	60	72	
Forward transfer admittance		Y _{fs}	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1.7 \text{ A}$	3.0	6.0	_	S
Input capacitance		C _{iss}			600		pF
Reverse transfer capacitance		C _{rss}	$V_{DS} = -10 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ f} = 1 \text{ MHz}$		60		
Output capacitance		C _{oss}			70		
Switching time	Rise time	tr	$V_{GS} \stackrel{0}{}_{-10} V \stackrel{I_D = -1.7 \text{ A}}{}_{} \stackrel{O}{}_{} \stackrel{O}{} \stackrel{O}{\overrightarrow$	_	5.3	_	- ns
	Turn-on time	t _{on}		_	12	_	
	Fall time	t _f		_	8.4	_	
	Turn-off time	t _{off}	Duty ≦ 1%, t _w = 10 μs	—	34	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -24 \text{ V}, \text{ V}_{GS} = -10 \text{ V},$		14		nC
Gate-source charge 1		Q _{gs1}	$I_{\rm D} = -3.4 \rm{A}$	_	1.4	_	
Gate-drain ("miller") charge		Q _{gd}		_	2.7		

Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	—	_	_	-13.6	А
Forward voltage (diode)		V _{DSF}	$I_{DR} = -3.4$ A, $V_{GS} = 0$ V	_	_	1.2	V

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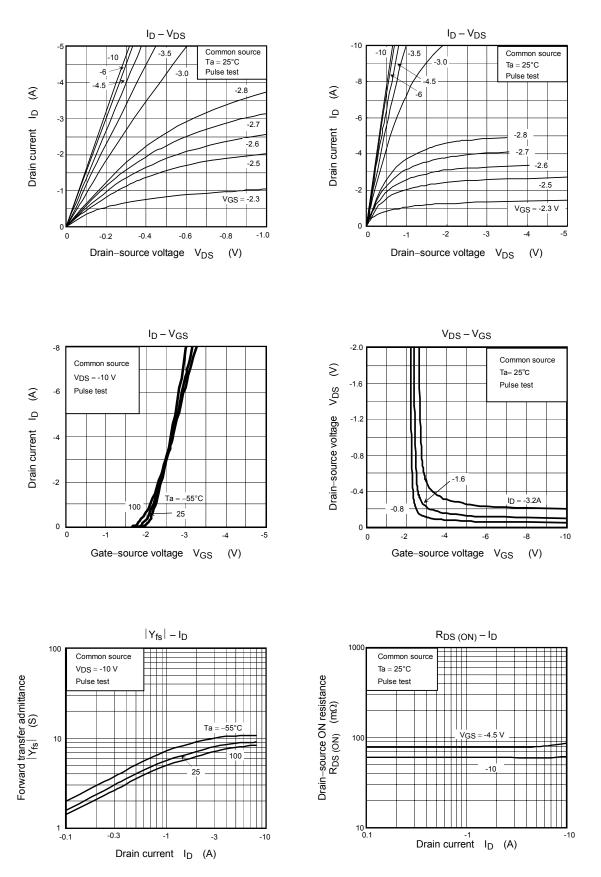
Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I _{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V	_		±10	μA
Drain cut-off curre	ent	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V	_		10	μA
Drain-source breakdown voltage		V (BR) DSS	R) DSS ID = 10 mA, V _{GS} = 0 V	30			V
		V (BR) DSX	I _D = 10 mA, V _{GS} = −20 V	15			v
Gate threshold vo	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	1.3		2.5	V
Drain-source ON resistance			V _{GS} = 4.5 V, I _D = 2.1 A		58	77	mΩ
		R _{DS (ON)}	V _{GS} = 10 V, I _D = 2.1 A		38	50	
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 2.1 A	3.5	7.0		S
Input capacitance		C _{iss}			470		pF
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	60	_	
Output capacitane	ce	C _{oss}			80		
	Rise time	tr	$V_{GS} \begin{array}{c} 10 \text{ V} \\ 0 \text{ V} \end{array} \begin{array}{c} I_{D} = 2.1 \text{ A} \\ I_{D} = 2.1 \text{ A} \\ 0 \text{ V} \\ 0 V$	_	5.2		
Switching time	Turn-on time	t _{on}			8.3	_	ns
Switching time	Fall time	tf			4.0	_	115
	Turn-off time	t _{off}			22	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	10	—	
Gate-source charge 1		Q _{gs1}	V _{DD} ≈ 24 V, V _{GS} = 10 V, I _D = 6 A	_	1.7	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	2.4	_	

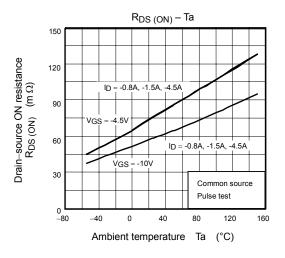
Source-Drain Ratings and Characteristics (Ta = 25°C)

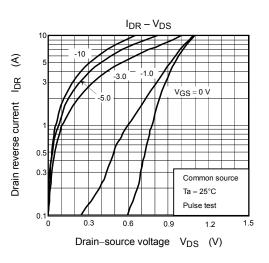
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	—	_	_	16.8	А
Forward voltage (diode)		V _{DSF}	I_{DR} = 4.2 A, V_{GS} = 0 V			-1.2	V

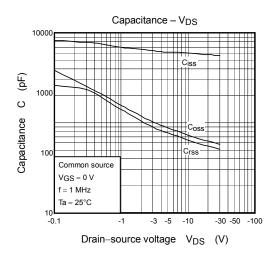
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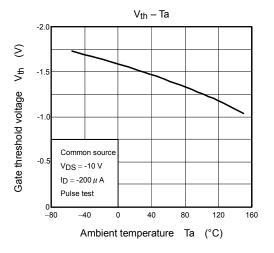


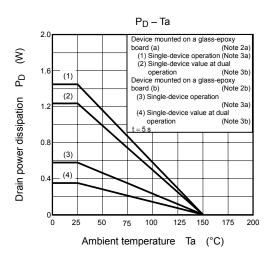
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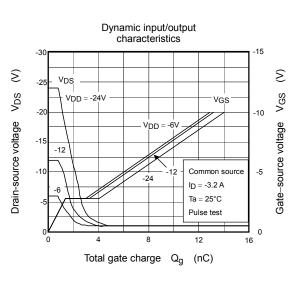




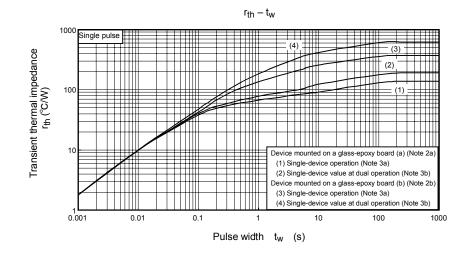


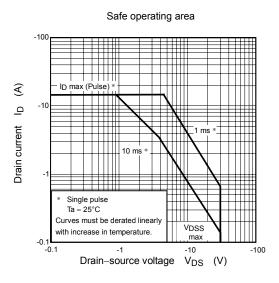




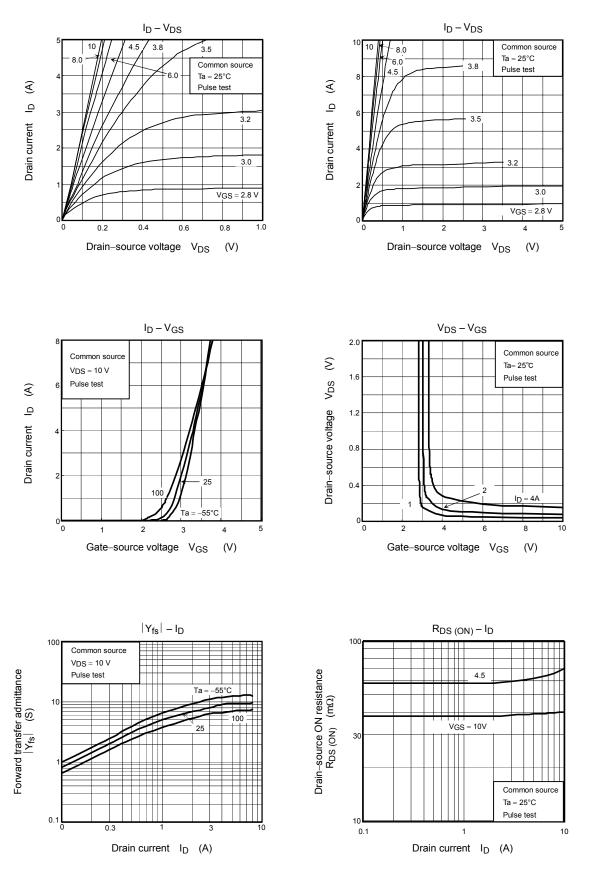


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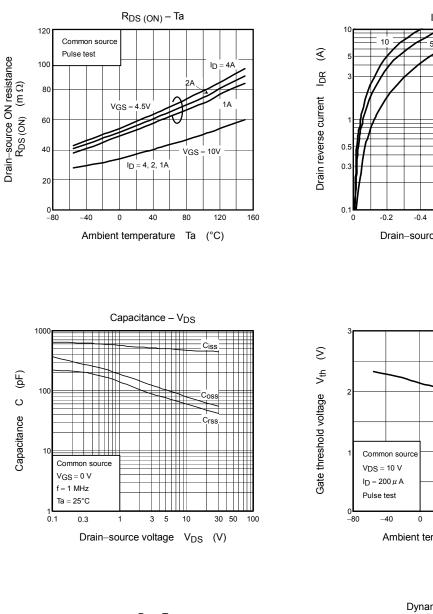


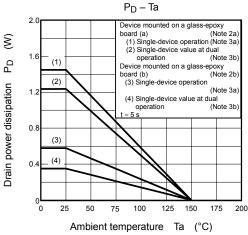


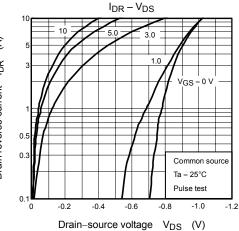
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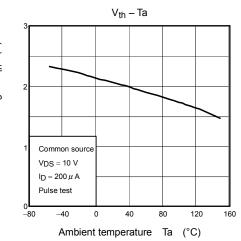


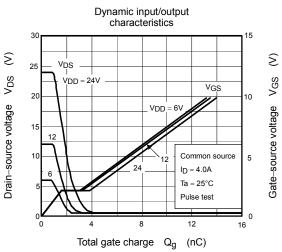
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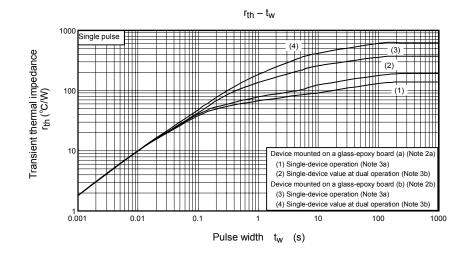


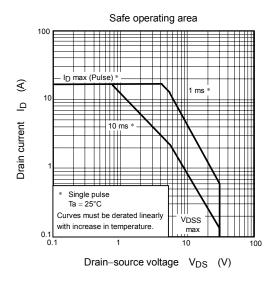






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